

10516583_CLS.txt
Most Frequently Occurring Classifications of Patents Returned
From A Search of 10516583 on June 06, 2006

Original Classifications

6 368/113
5 326/39
5 326/41
5 368/118
4 331/57
3 326/38
2 324/158.1
2 326/16
2 703/14
2 714/725

Cross-Reference Classifications

11 368/120
9 368/118
7 324/617
6 326/41
5 326/38
5 327/265
5 714/733
5 716/16
4 324/73.1
4 324/763
4 324/765
4 326/39
4 365/201
4 714/725
3 327/525
3 331/57
2 324/633
2 324/658
2 324/686
2 324/713
2 326/40
2 327/46
2 716/4

Combined Classifications

14 368/118
11 326/41
11 368/120
9 326/39
8 326/38
7 324/617
7 331/57
6 368/113
6 714/725
6 716/16
5 327/265
5 714/733
4 324/73.1
4 324/763
4 324/765
4 365/201
3 326/16
3 327/525
2 324/158.1
2 324/550
2 324/633

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2 324/658
2 324/686
2 324/713
2 326/40
2 327/46
2 703/14
2 714/717
2 716/4

10516583_QUAL.txt

5550839 69
5952852 61
6331790 61
6134191 58
6069849 58
6219305 58
6219305 58
6233205 58
6075418 58
6144262 58
6232845 58
6239611 58
5790479 58
6005829 58
6356514 58
6437597 58
6466520 58
6611477 58
5254886 56
5391942 56
5581199 56
5760604 56
5801546 56
5828230 56
6163167 56
6208163 56
5278841 52
5550843 52
5656949 52
5675589 52
5349248 52
5453696 52
5498979 52
5617021 52
5672966 52
5694047 52
5815404 52
6236229 52
5991907 50
6003150 50
6150863 50
5365513 50
5381348 50
5459342 50
5633813 50
6167001 50
6173424 50
6389379 50
6452459 50
6502050 50

Titles of Most Frequently Occurring Classifications of Patents Returned
From A Search of 10516583 on June 06, 2006

- 14 368/118 (5 OR, 9 XR)
Class 368 : HOROLOGY: TIME MEASURING SYSTEMS OR DEVICES
368/89 TIME INTERVAL
368/107 .Electrical or electromechanical
368/113 ..Stop time type
368/118 ...Including time base oscillator
- 11 326/41 (5 OR, 6 XR)
Class 326 : ELECTRONIC DIGITAL LOGIC CIRCUITRY
326/37 MULTIFUNCTIONAL OR PROGRAMMABLE (E.G.,
UNIVERSAL, ETC.)
326/39 .Array (e.g., PLA, PAL, PLD, etc.)
326/41 ..Significant integrated structure, layout, or
layout interconnections
- 11 368/120 (0 OR, 11 XR)
Class 368 : HOROLOGY: TIME MEASURING SYSTEMS OR DEVICES
368/89 TIME INTERVAL
368/107 .Electrical or electromechanical
368/113 ..Stop time type
368/120 ...Including delay means
- 9 326/39 (5 OR, 4 XR)
Class 326 : ELECTRONIC DIGITAL LOGIC CIRCUITRY
326/37 MULTIFUNCTIONAL OR PROGRAMMABLE (E.G.,
UNIVERSAL, ETC.)
326/39 .Array (e.g., PLA, PAL, PLD, etc.)
- 8 326/38 (3 OR, 5 XR)
Class 326 : ELECTRONIC DIGITAL LOGIC CIRCUITRY
326/37 MULTIFUNCTIONAL OR PROGRAMMABLE (E.G.,
UNIVERSAL, ETC.)
326/38 .Having details of setting or programming of
interconnections or logic functions
- 7 324/617 (0 OR, 7 XR)
Class 324 : ELECTRICITY: MEASURING AND TESTING
324/600 IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES
REPRESENTATIVE OF ELECTRICAL STIMULUS/RESPONSE
RELATIONSHIPS
324/612 .Parameter related to the reproduction or
fidelity of a signal affected by a circuit under test
324/615 ..Transfer function type characteristics
324/617 ...Response time or phase delay
- 7 331/57 (4 OR, 3 XR)
Class 331 : OSCILLATORS
331/57 RING OSCILLATORS
- 6 368/113 (6 OR, 0 XR)
Class 368 : HOROLOGY: TIME MEASURING SYSTEMS OR DEVICES
368/89 TIME INTERVAL
368/107 .Electrical or electromechanical
368/113 ..Stop time type
- 6 714/725 (2 OR, 4 XR)

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Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/724 .Digital logic testing
714/725 ..Programmable logic array (PLA) testing

6 716/16 (1 OR, 5 XR)
Class 716 : DATA PROCESSING: DESIGN AND ANALYSIS OF
CIRCUIT OR SEMICONDUCTOR MASK
716/1 CIRCUIT DESIGN
716/12 .Routing (e.g., routing map, netlisting)
716/16 ..PLA, PLD, FPGA, OR MCM

5 327/265 (0 OR, 5 XR)
Class 327 : MISCELLANEOUS ACTIVE ELECTRICAL NONLINEAR
DEVICES, CIRCUITS, AND SYSTEMS
327/100 SIGNAL CONVERTING, SHAPING, OR GENERATING
327/261 .Having specific delay in producing output
waveform
327/263 ..Delay interval set by rising or falling edge
327/264 ...Having specific active circuit element or
structure (e.g., FET, complementary transistors, etc.)
327/265With counter

5 714/733 (0 OR, 5 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/724 .Digital logic testing
714/733 ..Built-in testing circuit (BILBO)

4 324/73.1 (0 OR, 4 XR)
Class 324 : ELECTRICITY: MEASURING AND TESTING
324/73.1 PLURAL, AUTOMATICALLY SEQUENTIAL TESTS

4 324/763 (0 OR, 4 XR)
Class 324 : ELECTRICITY: MEASURING AND TESTING
324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF
ELECTRIC COMPONENTS
324/537 .Of individual circuit component or element
324/763 ..DUT including test circuit

4 324/765 (0 OR, 4 XR)
Class 324 : ELECTRICITY: MEASURING AND TESTING
324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF
ELECTRIC COMPONENTS
324/537 .Of individual circuit component or element
324/765 ..Test of semiconductor device

4 365/201 (0 OR, 4 XR)
Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL
365/189.01 READ/WRITE CIRCUIT
365/201 .Testing

3 326/16 (2 OR, 1 XR)
Class 326 : ELECTRONIC DIGITAL LOGIC CIRCUITRY
326/16 WITH TEST FACILITATING FEATURE

3 327/525 (0 OR, 3 XR)
Class 327 : MISCELLANEOUS ACTIVE ELECTRICAL NONLINEAR
DEVICES, CIRCUITS, AND SYSTEMS
327/524 SPECIFIC IDENTIFIABLE DEVICE, CIRCUIT, OR

SYSTEM

327/525 .Fusible link or intentional destruct circuit

- 2 324/158.1 (2 OR, 0 XR)
 Class 324 : ELECTRICITY: MEASURING AND TESTING
 324/158.1 MISCELLANEOUS
- 2 324/550 (1 OR, 1 XR)
 Class 324 : ELECTRICITY: MEASURING AND TESTING
 324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF
 ELECTRIC COMPONENTS
 324/537 .of individual circuit component or element
 324/550 ..Fuse
- 2 324/633 (0 OR, 2 XR)
 Class 324 : ELECTRICITY: MEASURING AND TESTING
 324/600 IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES
 REPRESENTATIVE OF ELECTRICAL STIMULUS/RESPONSE
 RELATIONSHIPS
 324/629 .Distributive type parameters
 324/633 ..Using resonant frequency
- 2 324/658 (0 OR, 2 XR)
 Class 324 : ELECTRICITY: MEASURING AND TESTING
 324/600 IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES
 REPRESENTATIVE OF ELECTRICAL STIMULUS/RESPONSE
 RELATIONSHIPS
 324/649 .Lumped type parameters
 324/658 ..Using capacitive type measurement
- 2 324/686 (0 OR, 2 XR)
 Class 324 : ELECTRICITY: MEASURING AND TESTING
 324/600 IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES
 REPRESENTATIVE OF ELECTRICAL STIMULUS/RESPONSE
 RELATIONSHIPS
 324/649 .Lumped type parameters
 324/658 ..Using capacitive type measurement
 324/686 ...With a capacitive sensing means
- 2 324/713 (0 OR, 2 XR)
 Class 324 : ELECTRICITY: MEASURING AND TESTING
 324/600 IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES
 REPRESENTATIVE OF ELECTRICAL STIMULUS/RESPONSE
 RELATIONSHIPS
 324/649 .Lumped type parameters
 324/691 ..Using resistance or conductance measurement
 324/713 ...With voltage or current signal evaluation
- 2 326/40 (0 OR, 2 XR)
 Class 326 : ELECTRONIC DIGITAL LOGIC CIRCUITRY
 326/37 MULTIFUNCTIONAL OR PROGRAMMABLE (E.G.,
 UNIVERSAL, ETC.)
 326/39 .Array (e.g., PLA, PAL, PLD, etc.)
 326/40 ..With flip-flop or sequential device
- 2 327/46 (0 OR, 2 XR)
 Class 327 : MISCELLANEOUS ACTIVE ELECTRICAL NONLINEAR
 DEVICES, CIRCUITS, AND SYSTEMS
 327/1 SPECIFIC SIGNAL DISCRIMINATING (E.G.,
 COMPARING, SELECTING, ETC.) WITHOUT SUBSEQUENT CONTROL

327/39	.By frequency
327/44	..With predetermined frequency selection
327/46	...Including plural frequency detection
2 703/14	(2 OR, 0 XR)
Class 703	: DATA PROCESSING: STRUCTURAL DESIGN, MODELING, SIMULATION, AND EMULATION
703/13	SIMULATING ELECTRONIC DEVICE OR ELECTRICAL SYSTEM
703/14	.Circuit simulation
2 714/717	(1 OR, 1 XR)
Class 714	: ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
714/699	PULSE OR DATA ERROR HANDLING
714/712	.Transmission facility testing
714/717	..Loop or ring configuration
2 716/4	(0 OR, 2 XR)
Class 716	: DATA PROCESSING: DESIGN AND ANALYSIS OF CIRCUIT OR SEMICONDUCTOR MASK
716/1	CIRCUIT DESIGN
716/4	.Testing or evaluating